This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claim 1(canceled)

Claim 11 (new): A method for examining a signal supply apparatus in which signals having specified voltages supplied from a plurality of signal supply sources are subject to impedance conversion, respectively, by a plurality of impedance conversion devices, and supplied to a plurality of output lines, respectively, the method comprising:

short-circuiting each of the plurality of output lines upon examination; and

comparing a current value detected on the short-circuited lines and a specified current value to thereby determine whether the signal supply apparatus is good or bad.

Claim 12 (new): A method for examining a signal supply apparatus in which signals are subject to impedance conversion by a plurality of impedance conversion devices, respectively, and supplied to a plurality of output lines, the method comprising:

short-circuiting each of the plurality of output lines upon examination; and

comparing a composite current consumption value for the plurality of impedance conversion devices and a specified current value to determine whether the signal supply apparatus is good or bad.

Claim 13 (new): A signal supply apparatus in which signals having specified voltages supplied from a plurality of signal supply sources are subject to impedance conversion, respectively, by a plurality of impedance conversion devices, and supplied to a plurality of output lines, respectively, comprising:

means for short-circuiting each of the plurality of output lines upon examination; and

means for comparing a current value detected on the short-circuited lines and a specified current value to thereby determine whether the signal supply apparatus is good or bad.

Claim 14 (new): A signal supply apparatus in which signals are subject to impedance conversion by a plurality of impedance conversion devices, respectively, and supplied to a plurality of output lines, comprising:

means for short-circuiting each of the plurality of output lines upon examination; and means for comparing a composite current consumption value for the plurality of impedance conversion devices and a specified current value to determine whether the signal supply apparatus is good or bad.

Claim 15 (new): A semiconductor device including a signal supply apparatus in which signals having specified voltages supplied from a plurality of signal supply sources are subject to impedance conversion, respectively, by a plurality of impedance conversion devices, and supplied to a plurality of output lines, respectively, wherein the signal supply apparatus comprises:

a plurality of switching elements provided for the corresponding respective plurality of output lines;

a test terminal for inputting a test signal that controls operation of each of the plurality of switching elements; and

a detection terminal that is connected to the short-circuited lines,

wherein the signal supply apparatus is examined by:

short-circuiting each of the plurality of output lines upon examination; and

comparing a current value detected on the short-circuited lines and a specified current value to thereby determine whether the signal supply apparatus is good or bad.

Claim 16 (new): A data line driver IC including a signal supply apparatus in which signals having specified voltages supplied from a plurality of signal supply sources are subject to impedance conversion, respectively, by a plurality of impedance conversion devices, and supplied to a plurality of output lines, respectively, wherein the signal supply apparatus comprises:

a plurality of switching elements provided for the corresponding respective plurality of output lines;

a test terminal for inputting a test signal that controls operation of each of the plurality of switching elements; and

a detection terminal that is connected to the short-circuited lines,

wherein the signal supply apparatus is examined by:

short-circuiting each of the plurality of output lines upon examination; and

comparing a current value detected on the short-circuited lines and a specified current value to thereby determine whether the signal supply apparatus is good or bad,

wherein the signal supply apparatus is used as a driver device to drive each of a plurality of data lines in a display section using electro-optical elements.

Claim 17 (new): A data line driver IC according to claim 16, wherein, after a voltage is supplied to the test terminal and each of the plurality of switching elements is operated, a voltage with a voltage width range corresponding to ±(LSB)/2 with respect to a signal having the specified voltage to be supplied to the electro-optical elements is supplied through the detection terminal to the short-circuit line, and a minimum value among the current values detected at the detection terminal in response thereto is compared with a specified current value to make a good-or-bad determination.

Claim 18 (new): A data line driver IC according to claim 17, wherein the specified voltage is set as a voltage that is supplied to the electro-optical element when the display section displays an intermediate gradation.

Claim 19 (new): An electro-optical apparatus comprising a data line driver IC including a signal supply apparatus in which signals having specified voltages supplied from a plurality of signal supply sources are subject to impedance conversion, respectively, by a plurality of impedance conversion devices, and supplied to a plurality of output lines, respectively, wherein the signal supply apparatus comprises:

a plurality of switching elements provided for the corresponding respective plurality of output lines;

a test terminal for inputting a test signal that controls operation of each of the plurality of switching elements; and

a detection terminal that is connected to the short-circuited lines,

wherein the signal supply apparatus is examined by:

short-circuiting each of the plurality of output lines upon examination; and

comparing a current value detected on the short-circuited lines and a specified current value to thereby determine whether the signal supply apparatus is good or bad, wherein the signal supply apparatus is used as a driver device to drive each of a plurality of data lines in a display section using electro-optical elements.

Claim 20 (new): An electronic apparatus comprising an electro-optical apparatus comprising a data line driver IC including a signal supply apparatus in which signals having specified voltages supplied from a plurality of signal supply sources are subject to impedance conversion, respectively, by a plurality of impedance conversion devices, and supplied to a plurality of output lines, respectively, wherein the signal supply apparatus comprises:

a plurality of switching elements provided for the corresponding respective plurality of output lines;

a test terminal for inputting a test signal that controls operation of each of the plurality of switching elements; and

a detection terminal that is connected to the short-circuited lines,

wherein the signal supply apparatus is examined by:

short-circuiting each of the plurality of output lines upon examination; and

comparing a current value detected on the short-circuited lines and a specified current value to thereby determine whether the signal supply apparatus is good or bad, wherein the signal supply apparatus is used as a driver device to drive each of a plurality of data lines in a display section using electro-optical elements.

Claim 21 (new): A signal supply apparatus in which signals having specified voltages supplied from a plurality of signal supply sources are subject to impedance conversion, respectively, by a plurality of impedance conversion devices, and supplied to a plurality of output lines, respectively, wherein the signal supply apparatus is adapted to be examined to determine whether the signal supply apparatus is good or bad, wherein the signal supply apparatus comprises:

a plurality of switching elements provided for the corresponding respective plurality of output lines, wherein the plurality of switching elements allow each of the plurality of output lines to be short circuited upon examination to thereby determine whether the signal supply apparatus is good or bad;

a test terminal for inputting a test signal that controls operation of each of the plurality of switching elements; and

a detection terminal that is connected to the short-circuited lines to thereby allow a current value detected on the short-circuited lines to be compared to a specified current value.

Claim 22 (new): A signal supply apparatus in which signals are subject to impedance conversion by a plurality of impedance conversion devices, respectively, and supplied to a plurality of output lines, wherein the signal supply apparatus is adapted to be examined to determine whether the signal supply apparatus is good or bad, wherein the signal supply apparatus comprises:

a plurality of switching elements provided for the corresponding respective plurality of output lines, wherein the plurality of switching elements allow each of the plurality of output lines to be short circuited upon examination to thereby determine whether the signal supply apparatus is good or bad;

a test terminal for inputting a test signal that controls operation of each of the plurality of switching elements;

a short-circuit line that short-circuits the plurality of output lines when the plurality of switching elements are operated; and

a detection terminal for detecting the composite current consumption value to thereby allow a composite current consumption value for the plurality of impedance conversion devices to be compared to a specified current value to determine whether the signal supply apparatus is good or bad.